## **DIELECTRIC PROPERTIES IN BaTiO<sub>3</sub> DERIVED CERAMICS**

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Ferroelectric materials have been intensively studied during the last decades because they are of great interest for many practical applications. Electronic ceramics currently dominate applications and baryum titanate (BaTiO<sub>3</sub>) is perhaps the best known example. Ferroelectrics are rapidly replacing low-dielectric materials in capacitors, computer memories and more exotic devices like phased-array radar (1-3). The purpose of the present work is to sinter baryum titanate perovskite at low temperature ( $t_{sint.} \leq 1000^{\circ}$ C) with the aid of fluorides and to determine the effect of the additives on the dielectic properties of BaTiO<sub>3</sub>.

The ceramic microstructure was systematically characterized by a scanning electron microscopy observation performed on fractured samples. Dielectric measurements were carried out in the frequency and temperature ranges 50 -  $4.10^7$ Hz and 150 - 450K, respectively. All measurements were computer controlled. At frequencies from 50 to  $3.10^5$ Hz the permittivity  $\varepsilon'_r$  exhibits a high maximum (>7000) at 283K, which is independent of the frequency. At higher frequencies (>10<sup>6</sup>Hz) a dielectric relaxation is observed. A minimum of the relaxation frequency and a maximum of the dielectric dispersion appear at each phase transition temperature.

## REFERENCES

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5<sup>èmes</sup> Journées Maghrébines des Sciences des Matériaux (JMSM'96), HAMMAMET, Tunisie, 8 - 10 Novembre, 1996